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 Application/Control No.	Applicant(s)/Patent under Reexamination
10/751,731	LEE ET AL.
Examiner	Art Unit
Thomas D. Alunkal	2627

SEARCHED					
Class	Subclass	Date	Examiner		
369	59.11	11/12/2007	TDA		
369	59.12	11/12/2007	TDA		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST-US- PGPUB;USPAT;USOCR;EPO;JPO;D ERWENT;IBM_TDM(see Search History Attached)	11/12/2007	TDA
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